## USSN: 10/539,886

## IN THE CLAIMS

The following is a listing of the claims in the present application with claim 1 shown as amended and claim 9 shown as cancelled:

## **Listing of Claims:**

1. (Currently Amended) A method for preparing a film structure of a ferroelectric single crystal, which comprises adhering a ferroelectric single crystal plate to a substrate by a conductive adhesive or metal layer, wherein the ferroelectric single crystal is a material having the composition of formula (I):

x(A)y(B)z(C)-p(P)n(N) (I)

wherein.

(A) is Pb(Mg1/3Nb2/3)O3 or Pb(Zn1/3Nb2/3)O3.

(B) is PbTiO3,

(C) is LiTaO3,

- (P) is a metal selected from the group consisting of Pt, Au, Ag, Pd and Rh,
- (N) is an oxide of a metal selected from the group consisting of Ni, Co, Fe, Sr, Sc, Ru, Cu and Cd,

x is a number in the range of 0.65 to 0.98,

y is a number in the range of 0.01 to 0.34,

z is a number in the range of 0.01 to 0.1, and

p and n are each independently a number in the range of 0.01 to 5.

- 2. (Previously Amended) The method of claim 1, wherein the single crystal plate is polished to a thickness of 1 to 100 µm before or after the adhesion with the substrate.
- 3. (Original) The method of claim 1, wherein the single crystal plate is adhered to the substrate by placing a conductive adhesive between the single crystal plate and the substrate and heat treating the resulting laminate containing the adhesive at a temperature ranging from room temperature to 150  $^{\circ}$ C for 1 to 24 hours to cure the adhesive.
- 4. (Original) The method of claim 3, wherein the conductive adhesive is a gold- or silver- containing epoxy paste, or a Pt-containing adhesive sol.
- 5. (Previously Amended) The method of claim 3, wherein the adhesive is applied using a plate equipped with a pressurizing rod having a round terminal portion made of an elastic rubber.
- 6. (Original) The method of claim 1, wherein the single crystal plate is adhered to the substrate by depositing a conductive metal on each surface of the single crystal plate and the substrate, combining the two conductive metal layers, and pressurizing and heat-treating the resulting laminate at a temperature of 100 to 600  $^{\circ}$ C.

- 7. (Original) The method of claim 6, which further comprises inserting a plate of a metal having a melting point lower than that of the conductive metal between the two conductive metal layers prior to the pressurizing and heat-treating step of the laminate.
- 8. (Original) The method of claim 1, wherein the ferroelectric single crystal has a dielectric constant of 1,000 or greater as measured in a film form.
  - 9. (Cancelled)
- 10. (Original) The method of claim 1, wherein the substrate comprises a layer of an oxide material selected from SiO<sub>2</sub>, MgO, Al<sub>2</sub>O<sub>3</sub> and ZnO, the oxide layer being contacted with the conductive adhesive layer.
- 11. (Original) The method of claim 1, which further comprises forming a conductive metal layer on the surface of the single crystal plate opposite to the adhesive layer by a sputtering or an electronic beam evaporation method.
- 12. (Previously Amended) A ferroelectric single crystal film structure prepared by a method according to claim 1.
- 13. (Original) An electric or electronic device comprising the ferroelectric single crystal film structure according to claim 12.